Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10663767	HIRAYAMA ET AL.	
Examiner	Art Unit	
Egan, Scott	2621	

SEARCHED					
Class	Subclass	Date	Examiner		
348	272-275, 280, 335, 340	12/13/06	SE		
438	29, 31, 69	12/13/06	SE		
257	432, 294	12/13/06	SE		

SEARCH NOTES				
Search Notes	Date	Examiner		
East BRS see attached	12/13/06	SE		
Spoke wiith Tuan Ho about moving Microlenses to colect light at different angles	12/13/06	SE		

INTERFERENCE SEARCH				
Subclass	Date	Examiner		

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